- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V_{CC} and GND Configurations Minimize High-Speed Switching Noise
- EPIC[™] (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

description

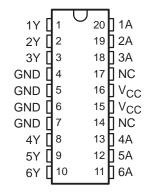
These devices contain six independent noninverters. They perform the Boolean function Y = A.

The 54AC11034 is characterized for operation over the full military temperature range of -55°C to 125°C. The 74AC11034 is characterized for operation from -40°C to 85°C.

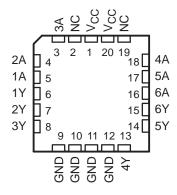
FUNCTION TABLE (each inverter)

INPUT A	OUTPUT Y
Н	Н
L	L

54AC11034 . . . J PACKAGE 74AC11034 . . . DW OR N PACKAGE (TOP VIEW)



54AC11034 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

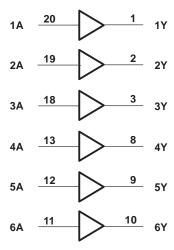
logic symbol†

1A	20	4	1 1Y
	19	<u>'</u>	2 2Y
2A	18		3 3Y
2A 3A 4A 5A	13		8 4Y
7 Δ	12		9 5Y
6A			10 6Y

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW, J, and N packages.

logic diagram (positive logic)



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SCAS034A - FEBRUARY 1988 - REVISED APRIL 1993

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	0 5 V to 7 V
Input voltage range, V _I (see Note 1)	5 V to V_{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	5 V to $V_{CC} + 0.5 V$
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±50 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±50 mA
Continuous current through V _{CC} or GND	±100 mA
Storage temperature range	. −65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

recommended operating conditions

			54	AC1103	4	74AC11034		UNIT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNII
VCC	Supply voltage		3	5	5.5	3	5	5.5	V
		V _{CC} = 3 V	2.1			2.1			
٧IH	High-level input voltage	$V_{CC} = 4.5 \text{ V}$	3.15			3.15			V
VIH High-le VIL Low-lev VI Input vo VO Output IOH High-le		V _{CC} = 5.5 V	3.85			3.85			
		VCC = 3 V			0.9			0.9	
VIL	Low-level input voltage	V _{CC} = 4.5 V			1.35			1.35	V
		V _{CC} = 5.5 V			1.65			1.65	
VI	Input voltage		0		VCC	0		VCC	V
Vo	Output voltage		0		VCC	0		VCC	V
		VCC = 3 V			-4			-4	
IOH	High-level output current	V _{CC} = 4.5 V			-24			-24	mA
		V _{CC} = 5.5 V			-24			-24	
		V _{CC} = 3 V			12			12	
lOL	Low-level output current	V _{CC} = 4.5 V			24			24	mA
		V _{CC} = 5.5 V			24			24	
Δt/Δν	Input transition rise or fall rate		0		10	0		10	ns/V
T _A	Operating free-air temperature		-55		125	-40		85	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T _A = 25°C			54AC1	1034	74AC1	UNIT	
PARAMETER	RAMETER TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Voн		3 V	2.9			2.9		2.9		
	ΙΟΗ = – 50 μΑ	4.5 V	4.4			4.4		4.4		
		5.5 V	5.4			5.4		5.4		
	I _{OH} = – 4 mA	3 V	2.58			2.4		2.48		\/
		4.5 V	3.94			3.7		3.8		V
	I _{OH} = -24 mA	5.5 V	4.94			4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V				3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V						3.85		
	Ι _{ΟL} = 50 μΑ	3 V			0.1		0.1		0.1	
		4.5 V			0.1		0.1		0.1	
		5.5 V			0.1		0.1		0.1	
VOL	I _{OL} = 12 mA	3 V			0.36		0.5		0.44	V
\ VOL	I _{OL} = 24 mA	4.5 V			0.36		0.5		0.44	V
		5.5 V			0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65			
	I _{OL} = 75 mA [†]	5.5 V							1.65	
lį	$V_I = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4		80		40	μΑ
C _i	V _I = V _{CC} or GND	5 V		3.5						pF

T Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 3.3 V \pm 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER		FROM	то	T _A = 25°C		54AC11034		74AC11034		UNIT	
PARAI	WEIER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
tpi	LH	А	A	1.5	5.7	9.1	1.5	10.7	1.5	10.1	no
tpi	HL		ſ	1.5	5.5	8.3	1.5	9.9	1.5	9.2	ns

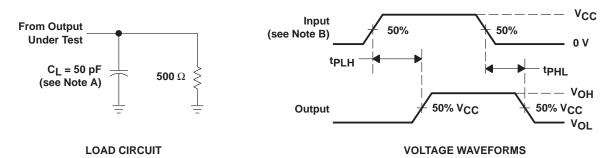
switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER FROM (INPUT)	FROM	FROM TO TA = 25°C		54AC11034		74AC11034		UNIT		
	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII	
t _{PLH}	А	Y	1.5	4	6.3	1.5	7.4	1.5	6.9	no
^t PHL			1.5	4	6.2	1.5	7.3	1.5	6.8	ns

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER		TEST CONDITIONS	TYP	UNIT
C _{pd}	Power dissipation capacitance per gate	$C_L = 50 \text{ pF}, \qquad f = 1 \text{ MHz}$	27	pF

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f = 3 \text{ ns}$, $t_f = 3 \text{ ns}$.
- C. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms

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